

Publications "Dimensional Nanometrology"

- Luigi Ribotta, Dimensional metrology at the nanoscale: quantitative characterization of nanoparticles by means of metrological atomic force microscopy, 2022, PhD Thesis in Metrology, Politecnico di Torino/INRiM, <https://iris.polito.it/handle/11583/2972877>
- Roberto Bellotti, Gian Bartolo Picotto, Luigi Ribotta, AFM Measurements of Nanoparticles with Different Shapes, Nanomanufacturing and Metrology, 2022, 12 pp, DOI:10.1007/s41871-022-00125-x
- Valter Maurino, Francesco Pellegrino, Gian Bartolo Picotto, Luigi Ribotta, Quantitative Three-Dimensional Characterization of Critical Sizes of Non-Spherical TiO₂ Nanoparticles by using Atomic Force Microscopy, Ultramicroscopy, 2022, 113480, DOI: 10.1016/j.ultramic.2022.113480
- Gian Bartolo Picotto, Marta Vallino, Luigi Ribotta, Tip-sample characterization in the AFM study of a rod-shaped nanostructure, Measurements Science and Technology, 31, 2020, 084001, DOI: 10.1088/2051-672X/aabe20